### **STL18N60M2**



## N-channel 600 V, 0.278 Ω typ., 9 A MDmesh II Plus™ low Qg Power MOSFET in a PowerFLAT™ 5x6 HV package

Datasheet - production data

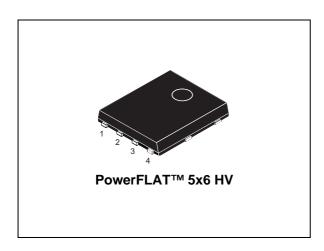
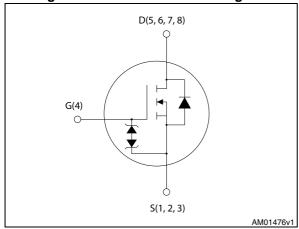


Figure 1. Internal schematic diagram



#### **Features**

| Order code | V <sub>DS</sub> @<br>T <sub>Jmax</sub> | R <sub>DS(on)</sub> max | I <sub>D</sub> |
|------------|--|-------------------------|----------------|
| STL18N60M2 | 650 V                                  | 0.308 Ω                 | 9 A            |

- Extremely low gate charge
- Lower R<sub>DS(on)</sub> x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

#### **Applications**

· Switching applications

#### **Description**

This device is an N-channel Power MOSFET developed using a new generation of MDmesh™ technology: MDmesh II Plus™ low Qg. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary** 

| Order code | Marking | Package           | Packaging     |
|------------|---------|-------------------|---------------|
| STL18N60M2 | 18N60M2 | PowerFLAT™ 5x6 HV | Tape and reel |

Contents STL18N60M2

## **Contents**

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STL18N60M2 Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol                          | Parameter   | Value       | Unit |
|---------------------------------|---|-------------|------|
| $V_{GS}$                        | Gate-source voltage   | ± 25        | V    |
| I <sub>D</sub> <sup>(1)</sup>   | Drain current (continuous) at T <sub>C</sub> = 25 °C  | 9           | Α    |
| I <sub>D</sub> <sup>(1)</sup>   | Drain current (continuous) at T <sub>C</sub> = 100 °C   | 5.5         | Α    |
| I <sub>DM</sub> <sup>(2)</sup>  | Drain current (pulsed)  | 22          | Α    |
| P <sub>TOT</sub> <sup>(2)</sup> | Total dissipation at T <sub>C</sub> = 25 °C   | 57          | W    |
| I <sub>AR</sub>                 | Avalanche current, repetitive or not-<br>repetitive (pulse width limited by T <sub>j</sub> max) | 2           | А    |
| E <sub>AS</sub>                 | Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)        | 135         | mJ   |
| dv/dt (3)                       | Peak diode recovery voltage slope   | 15          | V/ns |
| dv/dt (4)                       | MOSFET dv/dt ruggedness   | 50          | V/ns |
| T <sub>stg</sub>                | Storage temperature   | - 55 to 150 | °C   |
| T <sub>j</sub>                  | Max. operating junction temperature   | 150         | °C   |

<sup>1.</sup> The value is rated according to  $\mathbf{R}_{\text{thj-case}}$  and limited by package

Table 3. Thermal data

| Symbol                              | Parameter                            | Value | Unit |
|-------------------------------------|--------------------------------------|-------|------|
| R <sub>thj-case</sub>               | Thermal resistance junction-case max | 2.2   | °C/W |
| R <sub>thj-amb</sub> <sup>(1)</sup> | Thermal resistance junction-amb max  | 59    | °C/W |

<sup>1.</sup> When mounted on 1inch² FR-4 board, 2 oz Cu

<sup>2.</sup> Pulse width limited by safe operating area

<sup>3.</sup>  $I_{SD} \le 9$  A, di/dt  $\le 400$  A/ $\mu$ s,  $V_{DSpeak} \le V_{(BR)DSS}$ ,  $V_{DD} = 400$  V

 $<sup>4. \</sup>quad V_{DS} \leq 480 \ V$ 

Electrical characteristics STL18N60M2

## 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Table 4. On /off states

| Symbol               | Parameter                         | Test conditions  | Min. | Тур.  | Max.  | Unit |
|----------------------|-----------------------------------|--|------|-------|-------|------|
| V <sub>(BR)DSS</sub> | Drain-source<br>breakdown voltage | V <sub>GS</sub> = 0, I <sub>D</sub> = 1 mA                               | 600  |       |       | V    |
|                      | Zero gate voltage                 | $V_{GS} = 0, V_{DS} = 600 \text{ V}$                                     |      |       | 1     | μΑ   |
| I <sub>DSS</sub>     | drain current                     | V <sub>GS</sub> = 0, V <sub>DS</sub> = 600 V,<br>T <sub>C</sub> = 125 °C |      |       | 100   | μΑ   |
| I <sub>GSS</sub>     | Gate-body leakage current         | $V_{DS} = 0, V_{GS} = \pm 25 \text{ V}$                                  |      |       | 100   | nA   |
| V <sub>GS(th)</sub>  | Gate threshold voltage            | $V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$                               | 2    | 3     | 4     | V    |
| R <sub>DS(on)</sub>  | Static drain-source on-resistance | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.5 A                           |      | 0.278 | 0.308 | Ω    |

Table 5. Dynamic

| Symbol                              | Parameter                     | Test conditions                                   | Min. | Тур.  | Max. | Unit |
|-------------------------------------|-------------------------------|---|------|-------|------|------|
| C <sub>iss</sub>                    | Input capacitance             |   | -    | 791   | -    | pF   |
| C <sub>oss</sub>                    | Output capacitance            | $V_{GS} = 0, V_{DS} = 100 V,$                     | -    | 40    | -    | pF   |
| C <sub>rss</sub>                    | Reverse transfer capacitance  | f = 1 MHz,  | -    | 1.3   | -    | pF   |
| C <sub>oss eq.</sub> <sup>(1)</sup> | Output equivalent capacitance | V <sub>GS</sub> = 0, V <sub>DS</sub> = 0 to 480 V | -    | 164.5 | -    | pF   |
| R <sub>G</sub>                      | Intrinsic gate resistance     | f = 1 MHz, I <sub>D</sub> =0                      | -    | 5.6   | -    | Ω    |
| Qg                                  | Total gate charge             | V <sub>DD</sub> = 480 V, I <sub>D</sub> = 13 A,   | -    | 21.5  | -    | nC   |
| Q <sub>gs</sub>                     | Gate-source charge            | V <sub>GS</sub> = 10 V                            | -    | 3.2   | -    | nC   |
| Q <sub>gd</sub>                     | Gate-drain charge             | (see Figure 15)                                   | -    | 11.3  | -    | nC   |

<sup>1.</sup>  $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DS}$ .

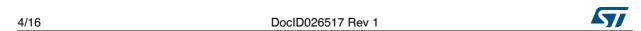


Table 6. Switching times

| Symbol              | Parameter          | Test conditions   | Min. | Тур. | Max | Unit |
|---------------------|--------------------|---|------|------|-----|------|
| t <sub>d(on)</sub>  | Turn-on delay time | $V_{DD} = 300 \text{ V}, I_{D} = 6.5 \text{ A},$<br>$R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ | -    | 12   | -   | ns   |
| t <sub>r</sub>      | Rise time          |   | -    | 9    | -   | ns   |
| t <sub>d(off)</sub> | Turn-on delay time | n <sub>G</sub> = 4.7 \(\frac{12}{2}\), v <sub>GS</sub> = 10 \(\frac{1}{2}\)                     | -    | 47   | -   | ns   |
| t <sub>f</sub>      | Fall time          | ,   | -    | 10.6 | -   | ns   |

Table 7. Source drain diode

| Symbol                          | Parameter                     | Test conditions  | Min. | Тур. | Max. | Unit |
|---------------------------------|-------------------------------|--|------|------|------|------|
| I <sub>SD</sub>                 | Source-drain current          |  | -    |      | 9    | Α    |
| I <sub>SDM</sub> <sup>(1)</sup> | Source-drain current (pulsed) |  | -    |      | 36   | Α    |
| V <sub>SD</sub> (2)             | Forward on voltage            | V <sub>GS</sub> = 0, I <sub>SD</sub> = 13 A                | -    |      | 1.6  | ٧    |
| t <sub>rr</sub>                 | Reverse recovery time         | I <sub>SD</sub> = 13 A, di/dt = 100 A/μs                   | -    | 305  |      | ns   |
| Q <sub>rr</sub>                 | Reverse recovery charge       | V <sub>DD</sub> = 60 V                                     | -    | 3.3  |      | μC   |
| I <sub>RRM</sub>                | Reverse recovery current      | (see Figure 16)  | -    | 22   |      | Α    |
| t <sub>rr</sub>                 | Reverse recovery time         | V <sub>DD</sub> = 60 V                                     | -    | 417  |      | ns   |
| Q <sub>rr</sub>                 | Reverse recovery charge       | $di/dt = 100 \text{ A}/\mu\text{s}, I_{SD} = 13 \text{ A}$ | -    | 4.6  |      | μC   |
| I <sub>RRM</sub>                | Reverse recovery current      | T <sub>j</sub> =150 °C (see <i>Figure 16</i> )             | -    | 22.2 |      | Α    |

<sup>1.</sup> Pulse width limited by safe operating area.

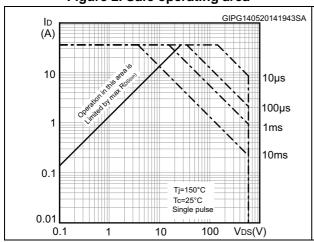
<sup>2.</sup> Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

Electrical characteristics STL18N60M2

### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance



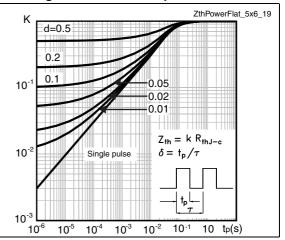
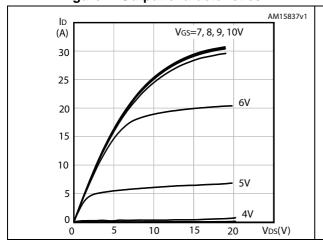


Figure 4. Output characteristics

Figure 5. Transfer characteristics



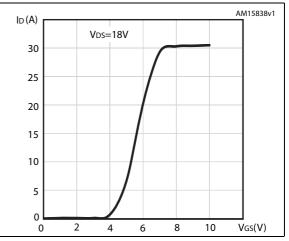
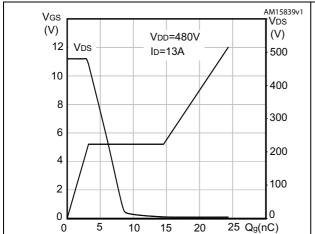
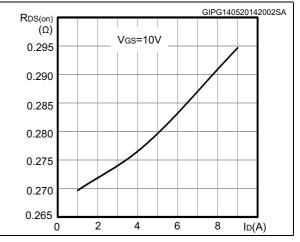


Figure 6. Gate charge vs gate-source voltage

Figure 7. Static drain-source on-resistance

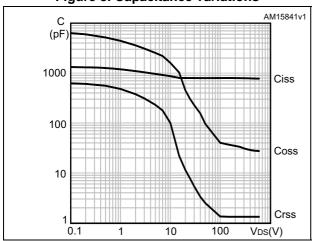




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Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy



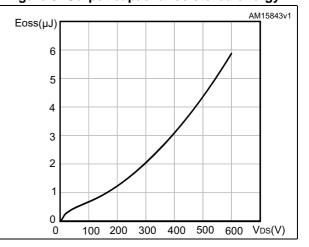
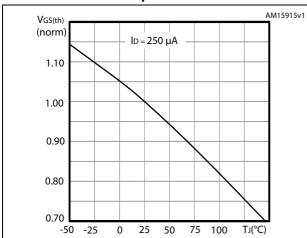


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on-resistance vs temperature



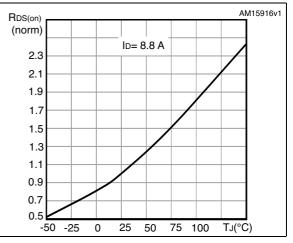
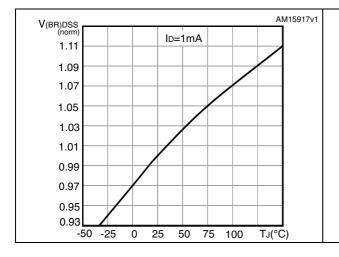
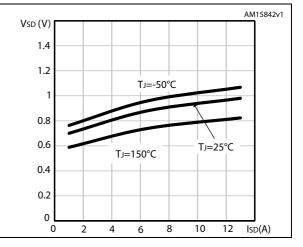


Figure 12. Normalized V<sub>(BR)DSS</sub> vs temperature

Figure 13. Source-drain diode forward characteristics





Test circuits STL18N60M2

## 3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

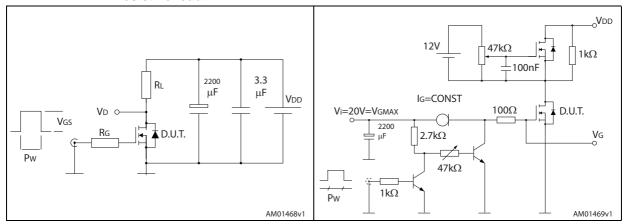


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

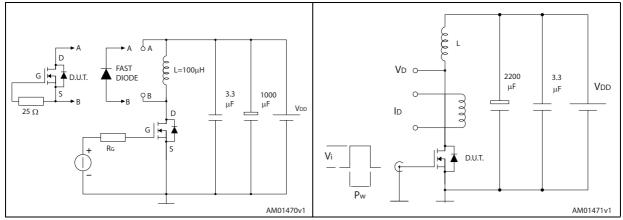
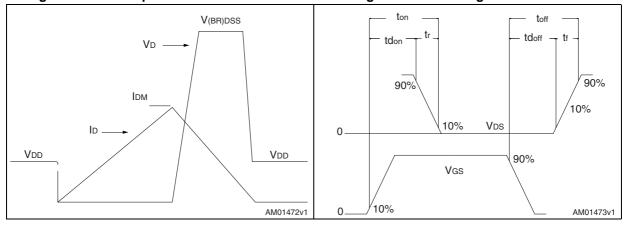


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



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# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



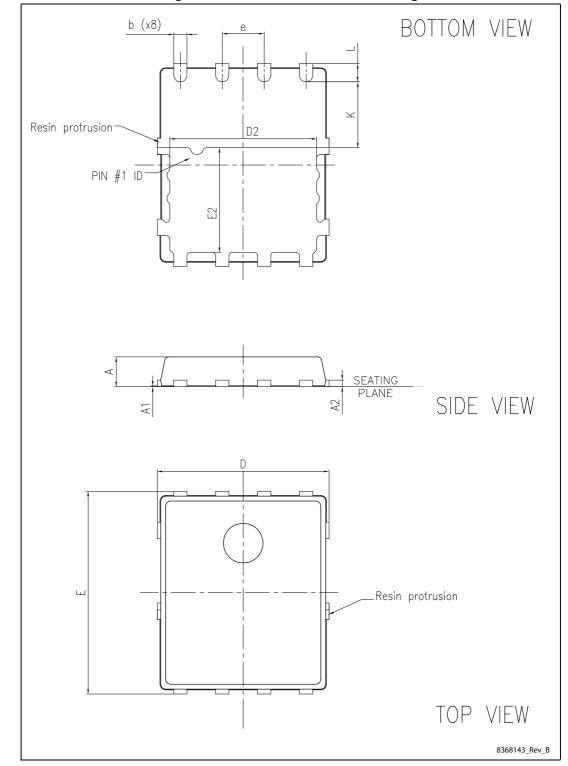


Figure 20. PowerFLAT™ 5x6 HV drawing

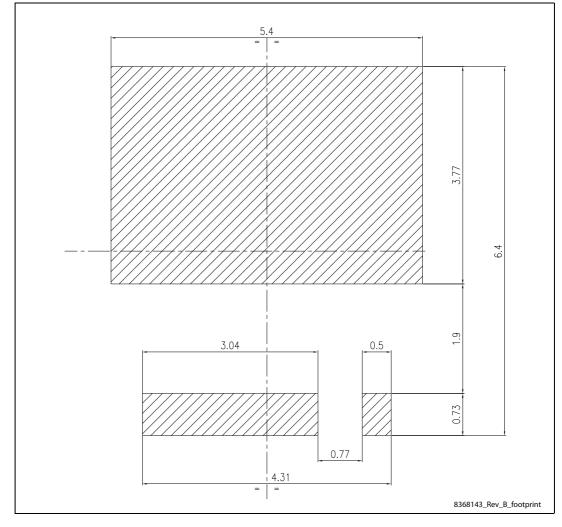


Figure 21. PowerFLAT™ 5x6 HV recommended footprint (dimensions are in mm)

Table 8. PowerFLAT™ 5x6 HV mechanical data

| Dim.   |      | mm   |      |
|--------|------|------|------|
| Dilli. | Min. | Тур. | Max. |
| А      | 0.80 |      | 1.00 |
| A1     | 0.02 |      | 0.05 |
| A2     |      | 0.25 |      |
| b      | 0.30 |      | 0.50 |
| D      | 5.00 | 5.20 | 5.40 |
| E      | 5.95 | 6.15 | 6.35 |
| D2     | 4.30 | 4.40 | 4.50 |
| E2     | 3.10 | 3.20 | 3.30 |
| е      |      | 1.27 |      |
| L      | 0.50 | 0.55 | 0.60 |
| K      | 1.90 | 2.00 | 2.10 |

# 5 Packaging mechanical data

Ko (1.20±0.1)

(I) Measured from centerline of sprocket hole to centerline of pocket.

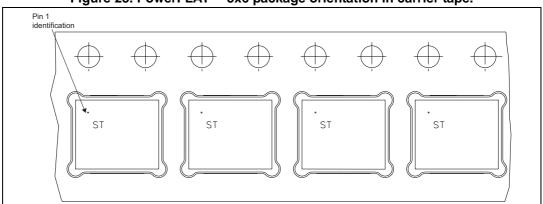
 $\label{eq:continuous} \begin{tabular}{ll} (II) & Cumulative tolerance of 10 sprocket holes is <math display="inline">\pm~0.20~. \end{tabular}$  (III) Measured from centerline of sprocket hole to centerline of pocket.

SECTION Y-Y

Figure 22. PowerFLAT™ 5x6 tape<sup>(a)</sup>



Base and bulk quantity 3000 pcs



a. All dimensions are in millimeters.



8234350\_Tape\_rev\_C

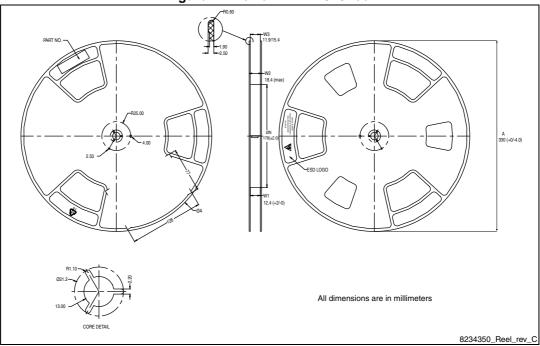


Figure 24. PowerFLAT™ 5x6 reel

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STL18N60M2 Revision history

# 6 Revision history

Table 9. Document revision history

| Date        | Revision | Changes        |
|-------------|----------|----------------|
| 12-Jun-2014 | 1        | First release. |

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